



Design of the first full-scale HYLITE, a charge integration pixel detector readout chip for XFEL

Introduction of SHINE, STARLIGHT and HYLITE



Figure 1 Location of SHINE (Top View)

• **SHINE (Shanghai High repetition rate XFEL and Extreme light facility)** is the first hard X-ray Free Electron Laser facility in China.

- Photon Energy: 0.4~25 keV
- Repetition Frequency: 10 kHz (Up to 1 MHz)

• **STARLIGHT (Semiconductor Array detector with Large dynamic range and charge integrating readout)** is a new pixel array detector designed for SHINE.

Specs	Parameters
Sensor	500 μm silicon PIN
Pixel Size	100μm × 100μm
Array Size	128 × 128
Dynamic range	1 ~ 10000 ph./pulse/pixel @12 keV
Frame rate	12 kHz (continuous readout)
Detector	A 4M pixel detector in vacuum, quadrant movable

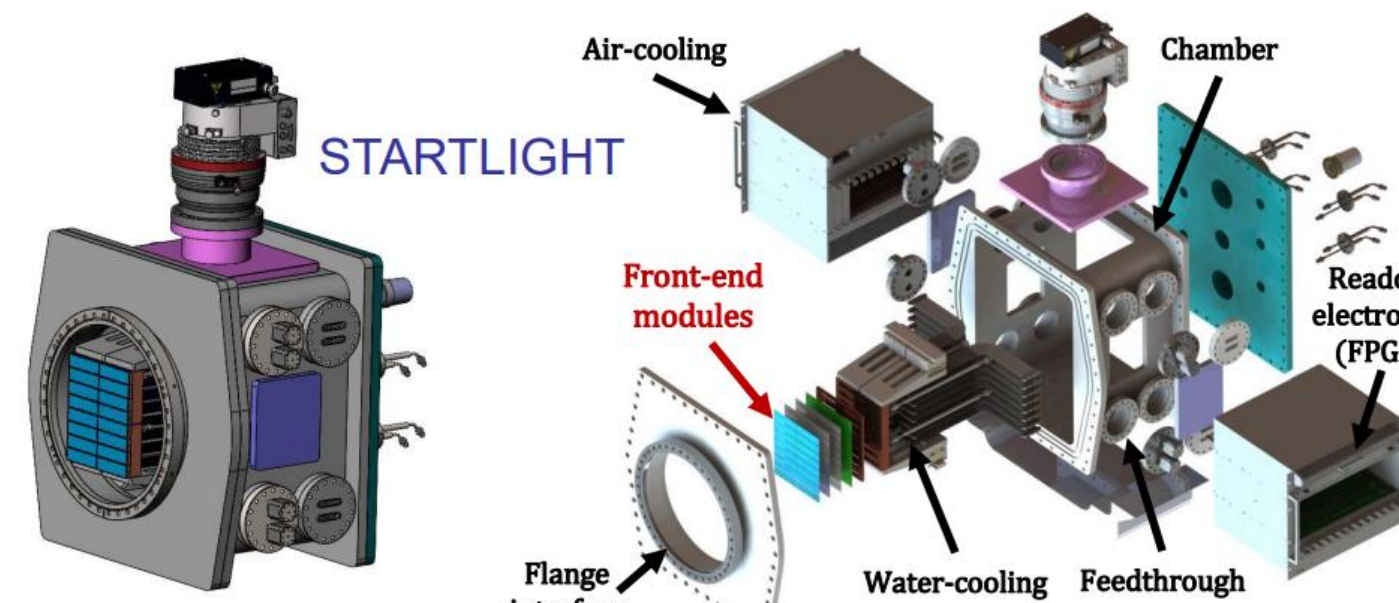
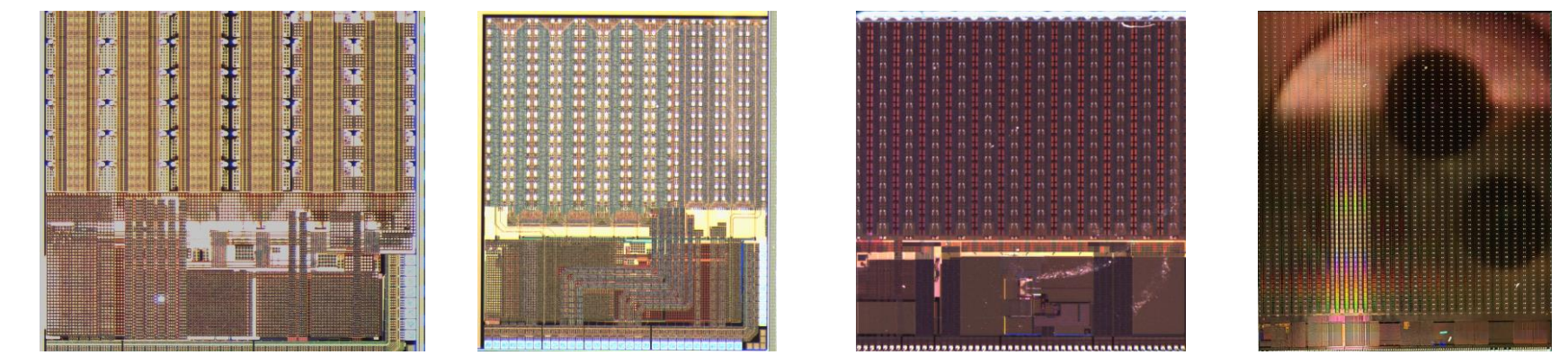


Figure 2 The STARLIGHT Detector System

• **HYLITE (High dynamic range free electron Laser Imaging deTEctor)** is the charge-integration pixel readout chip of STARLIGHT.



HILITE0.1

HYLITE0.2

HYLITE200S

HYLITE200F

- Tapeout: 2020.10
- Pixel size: 200μm×200μm
- Array Size: 6×12

- Tapeout: 2021.1
- Pixel size: 100μm×100μm
- Array Size: 16×24

- Tapeout: 2022.3
- Pixel size: 200μm×200μm
- Array Size: 16×25
- Full Function Verification

- Tapeout: 2022.6
- Pixel size: 200μm×200μm
- Array Size: 64×64
- First Full-Scale Chip

Chip Design

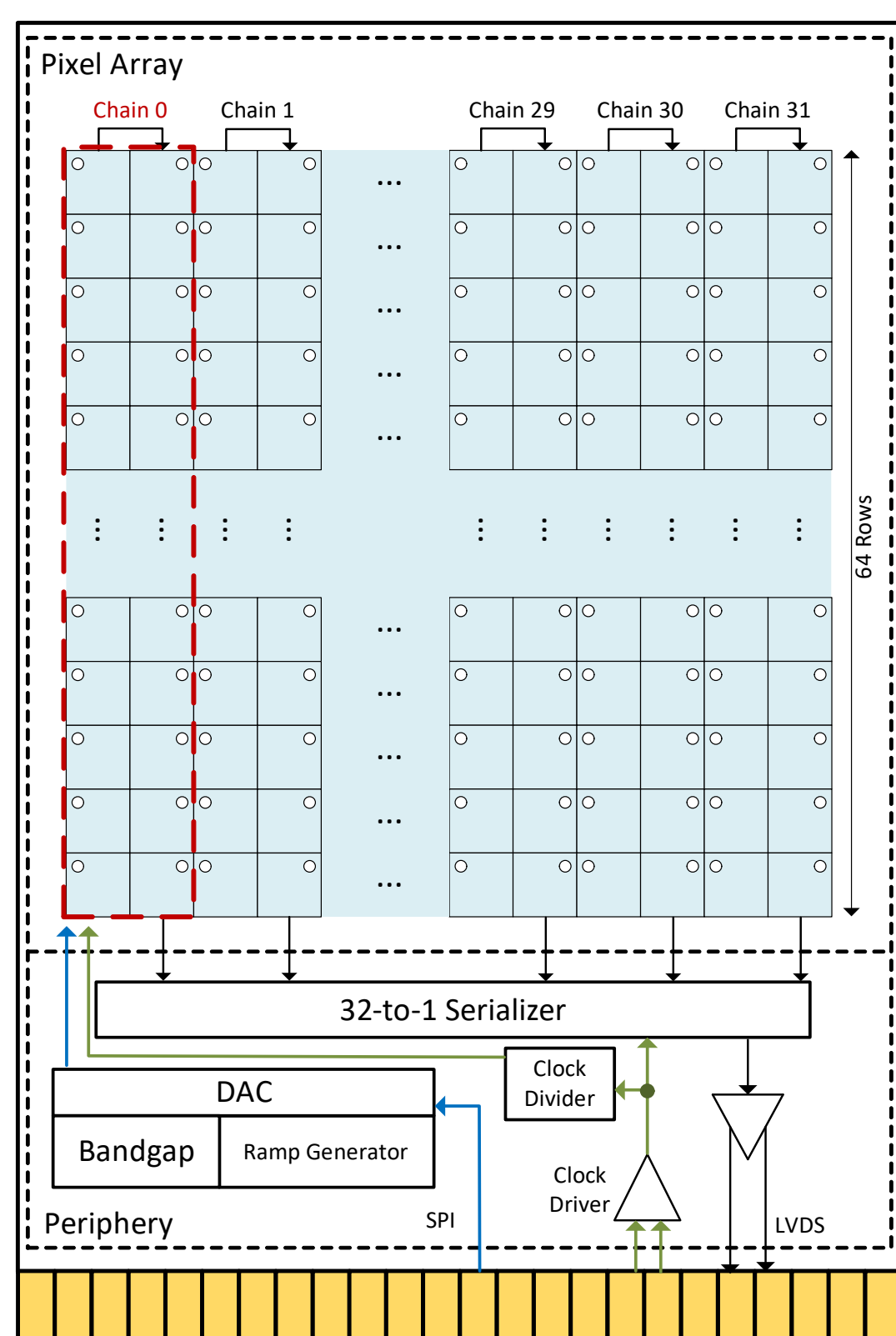


Figure 3 Block Diagram of the HYLITE200S Chip

• **HYLITE200F: The first full-scale chip of HYLITE.**

- Array Size: 64 × 64
- Pixel Size: 200 μm × 200 μm
- ENC in the High Gain Mode: ~360 e-
- Working in Pump-Probe mode, synced with the beamline.
- Three Gains
 - Automatic Gain Switching
 - Dynamic range of 10⁴ ph. @12 keV with single-photon resolution

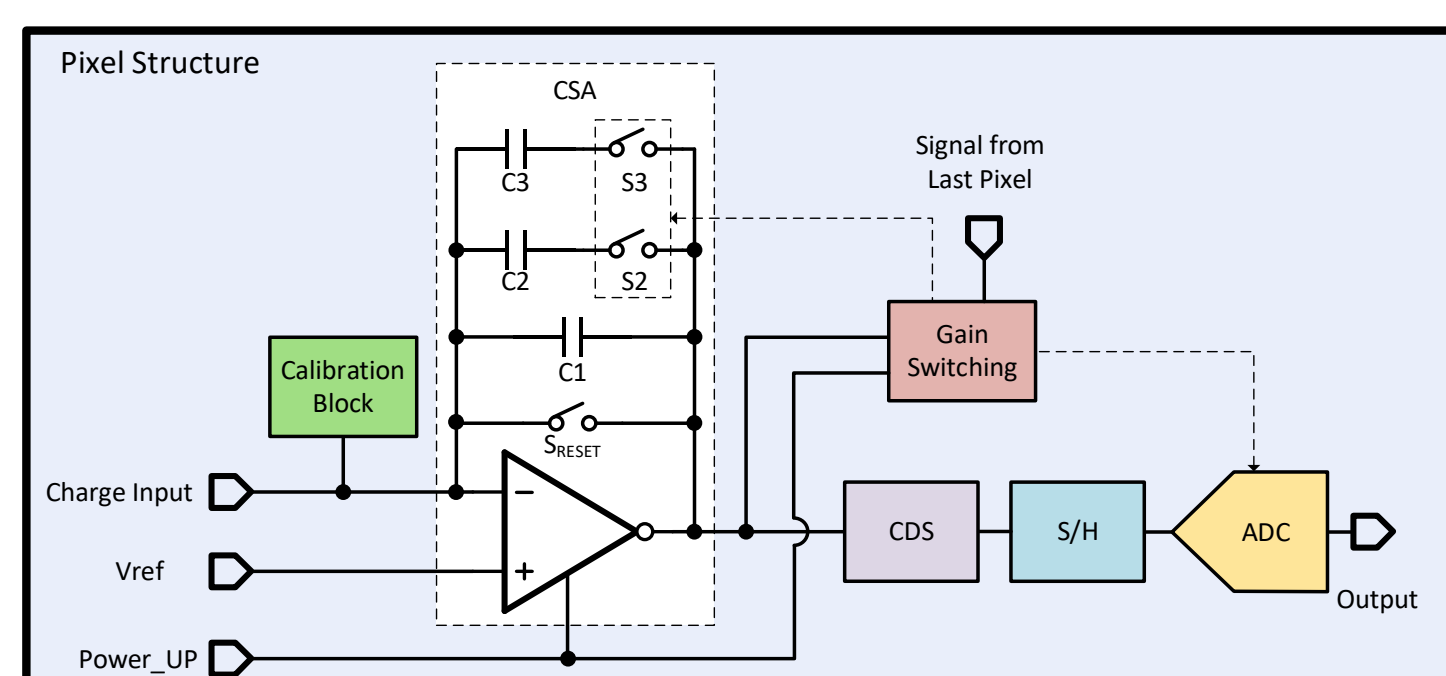


Figure 4 Block Diagram of the HYLITE Pixel Structure

- Three Working Phases
 - Analog Phase: Charge integration
 - Conversion Phase: A-D Conversion by in-pixel single-slope ADC
 - Readout Phase: Pixels organized as 32 shift chains; single LVDS output port
- Maximum Frame Rate @ 400 MHz external clock: 6.3 kHz
- Power down feature involved
 - Total average power: 34 μW/pixel
 - Analog: 21.96 μW (@ 1 μs analog power-up time)
 - Digital: 14.76 μW

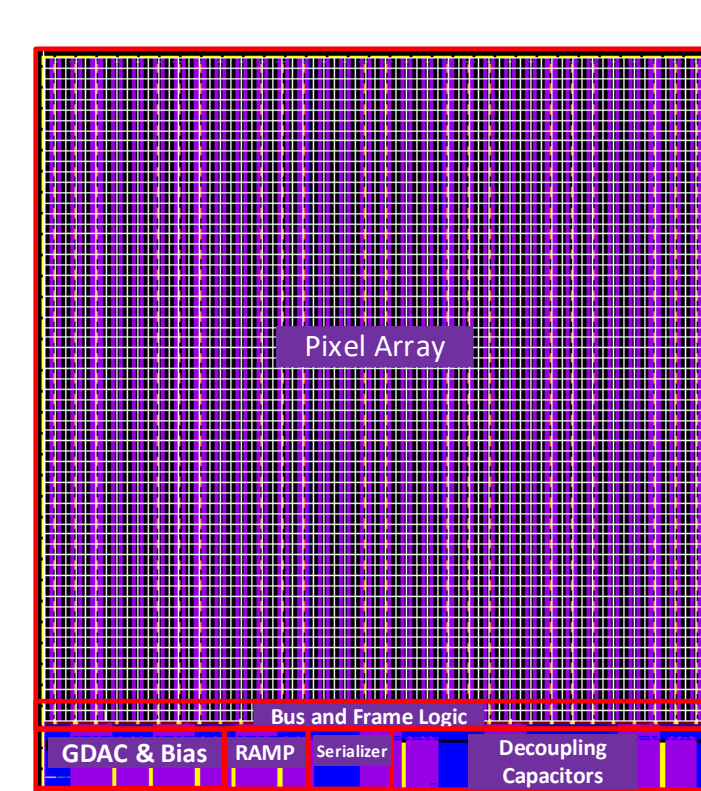


Figure 5 Pixel Layout of HYLITE200F

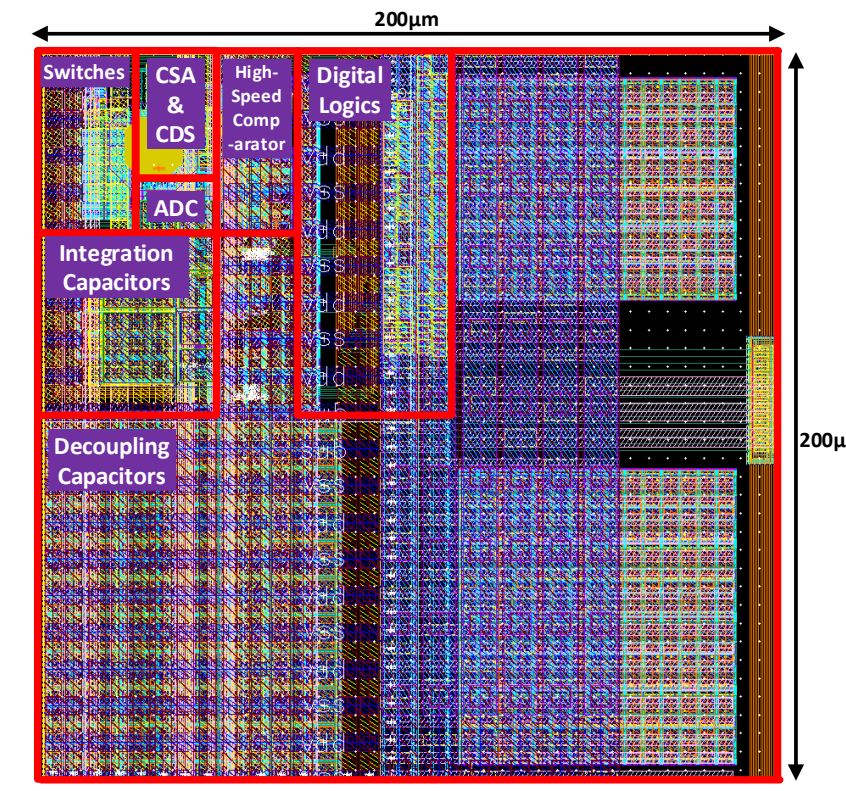


Figure 6 Chip Layout of HYLITE200F

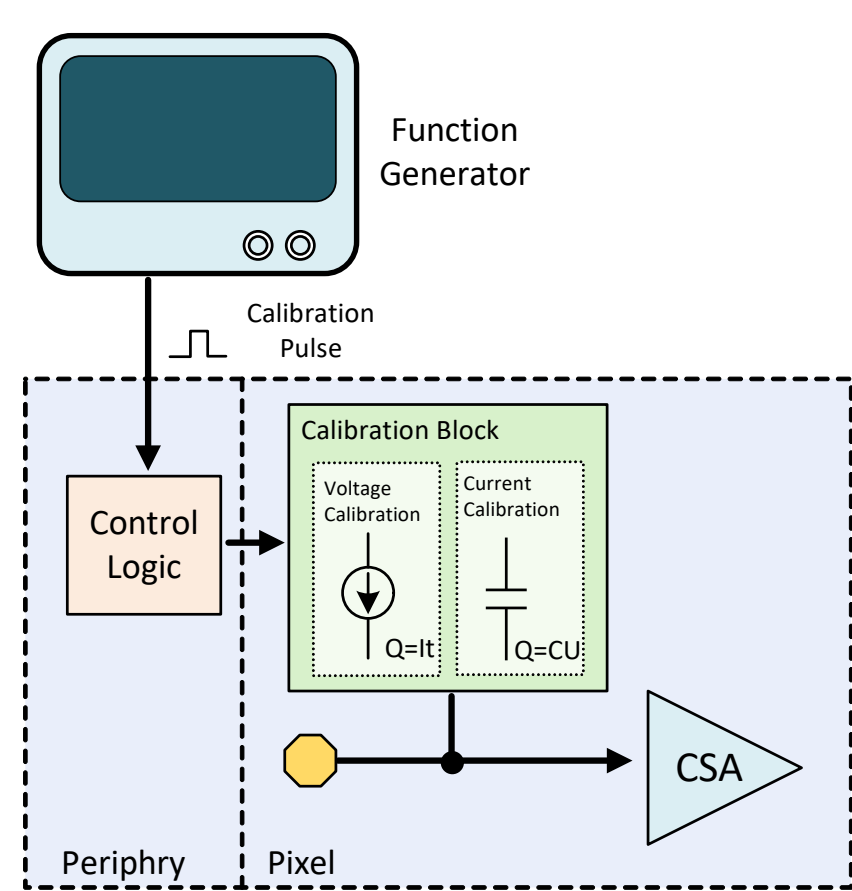


Figure 7 Chip Test Sources

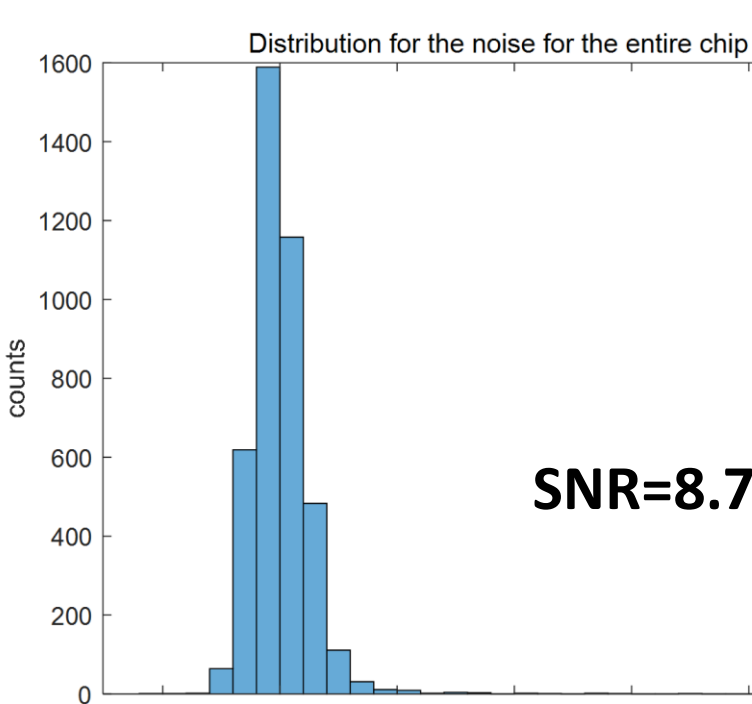


Figure 8 Noise Test Result

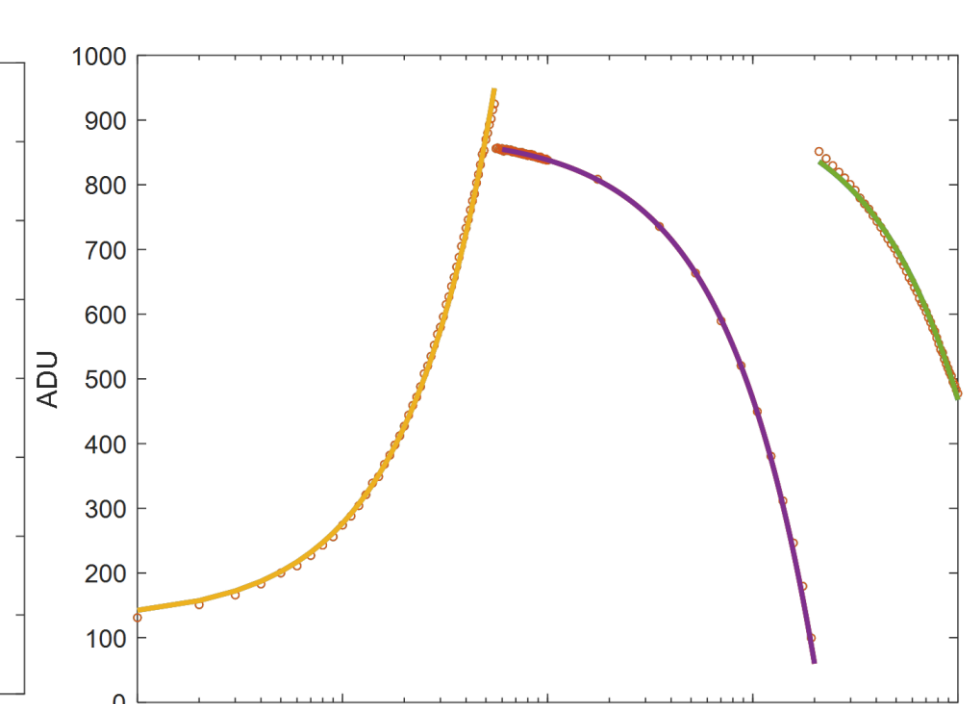


Figure 9 Dynamic Range Test of 10000 Photons

Wafer Test

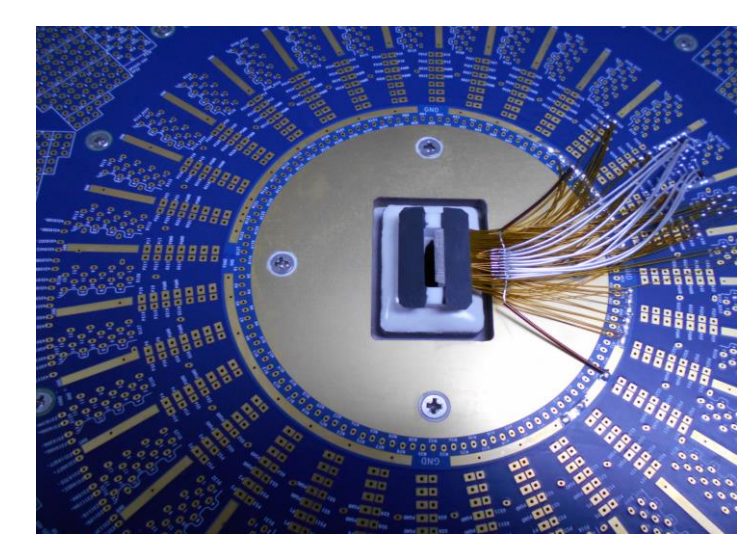
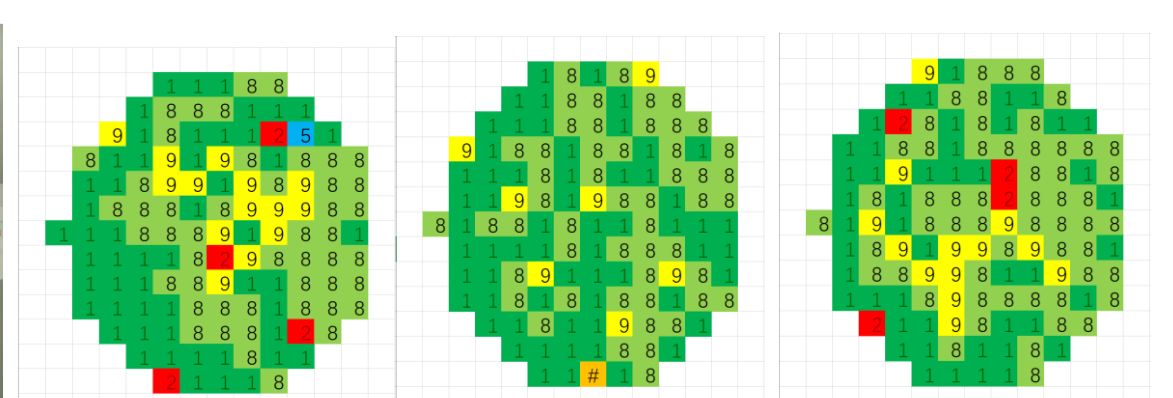


Figure 10 The wafer probe card and test environment of HYLITE200F



- Average yield of 5 wafers: 84.8%

Prototype Modules

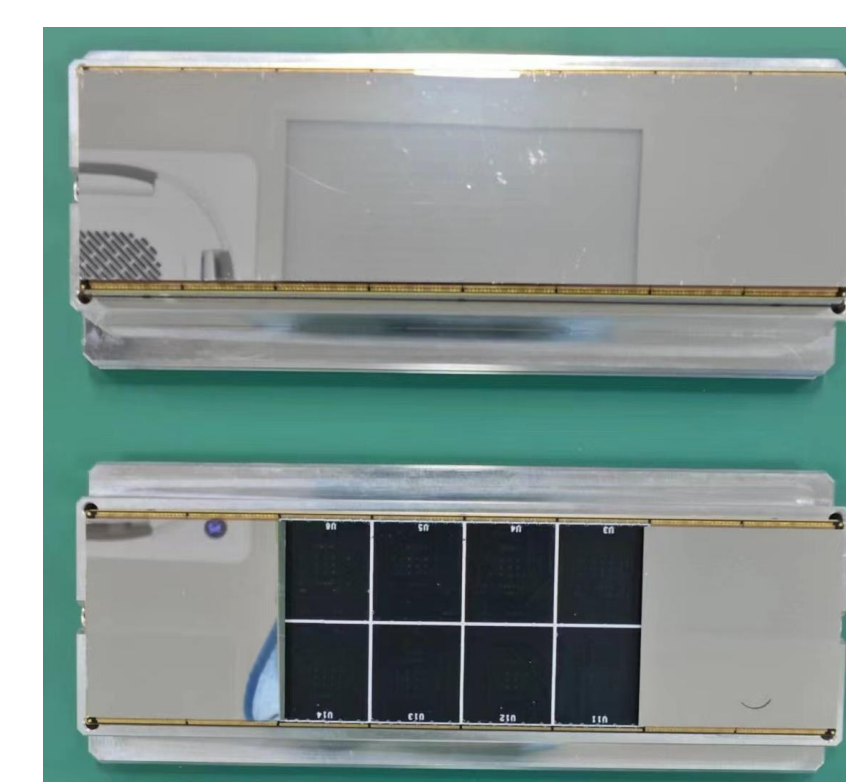


Figure 11 Modules of 2×8 & 2×2 Chips

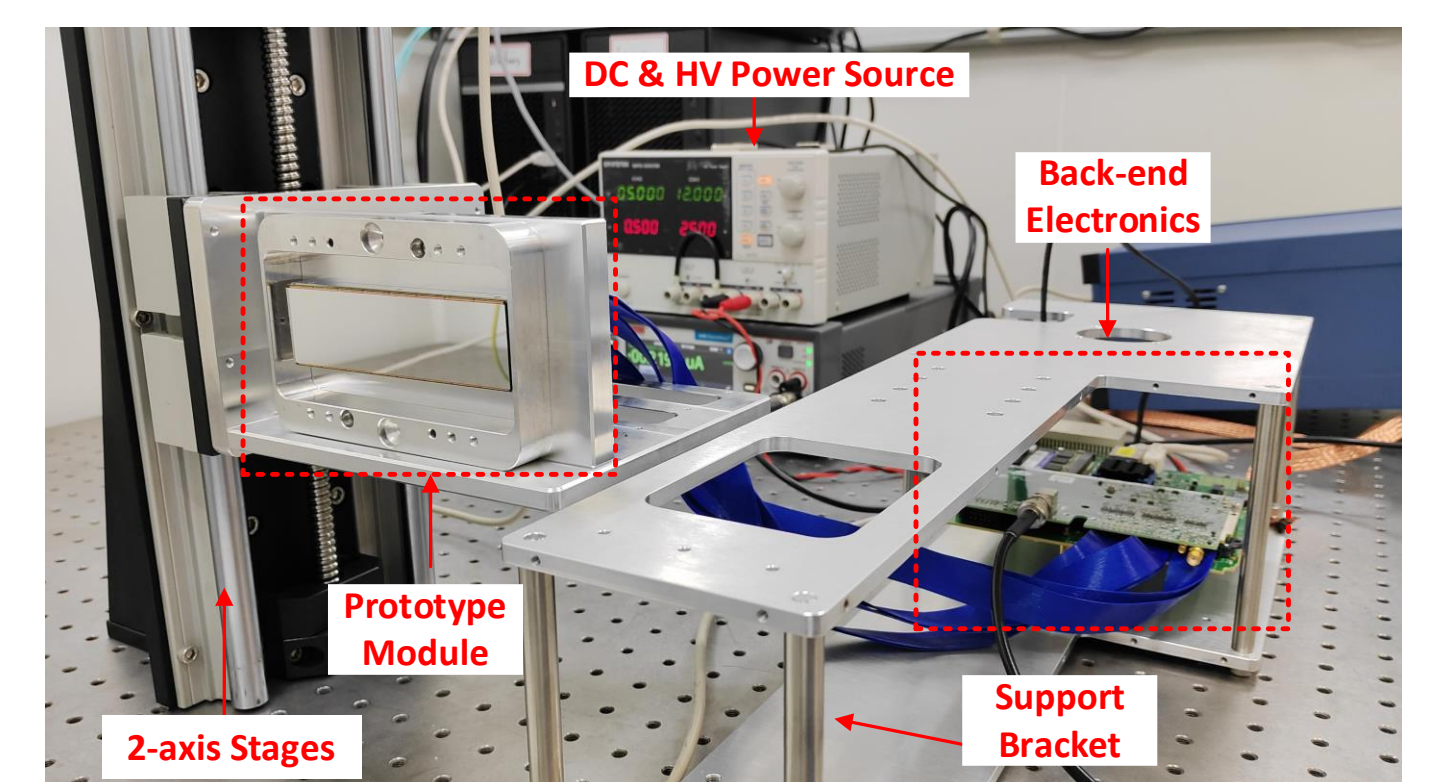


Figure 12 Test environment of prototype modules

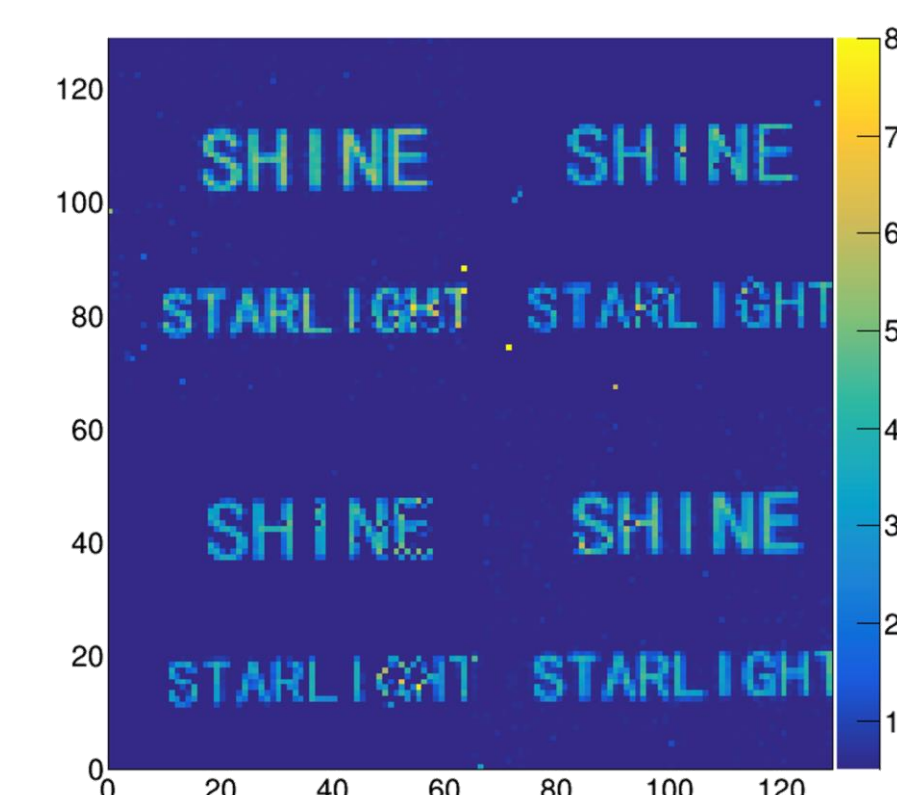


Figure 13 Imaging test with a "SHINE STRALIGHT" mask, module of 2×2 Chips

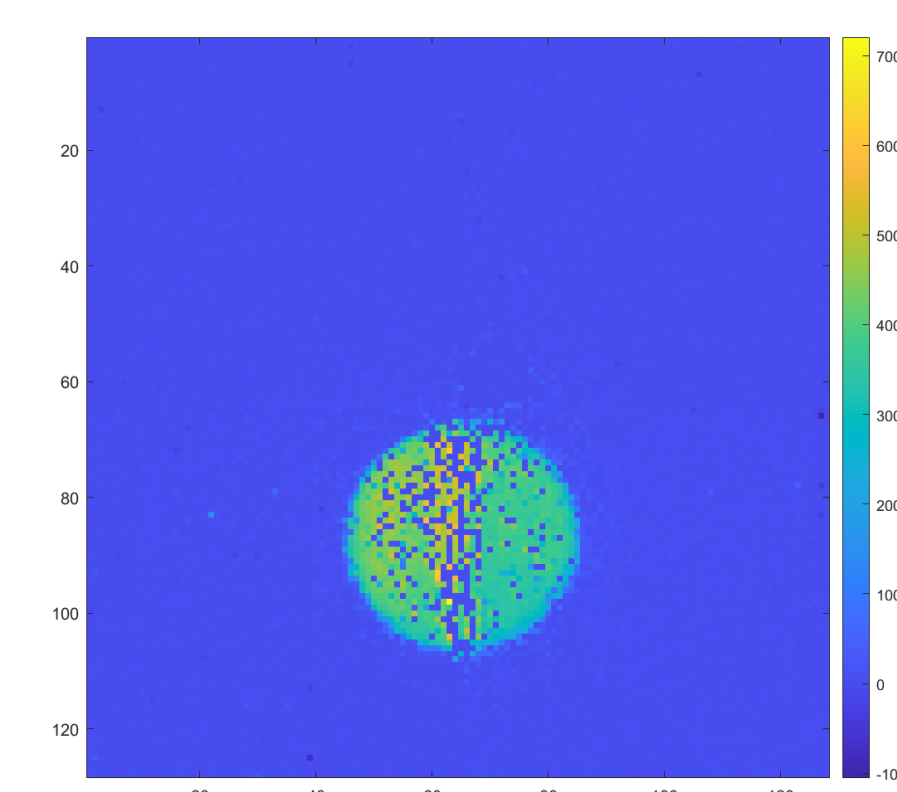


Figure 14 Imaging test with a light dot, module of 2×2 Chips

- Sensor: 500 μm silicon PIN
- Bump-bonding
 - Copper Pillar technology
 - Minimum pad clearance: 60 μm
- Three types of prototypes are manufactured
 - Single Chip (Fully tested, referring Poster #15)
 - 2×2 Chips (Preliminarily tested)
 - 2×8 Chips (Under tested)

• **Functionality of the detector is verified.**

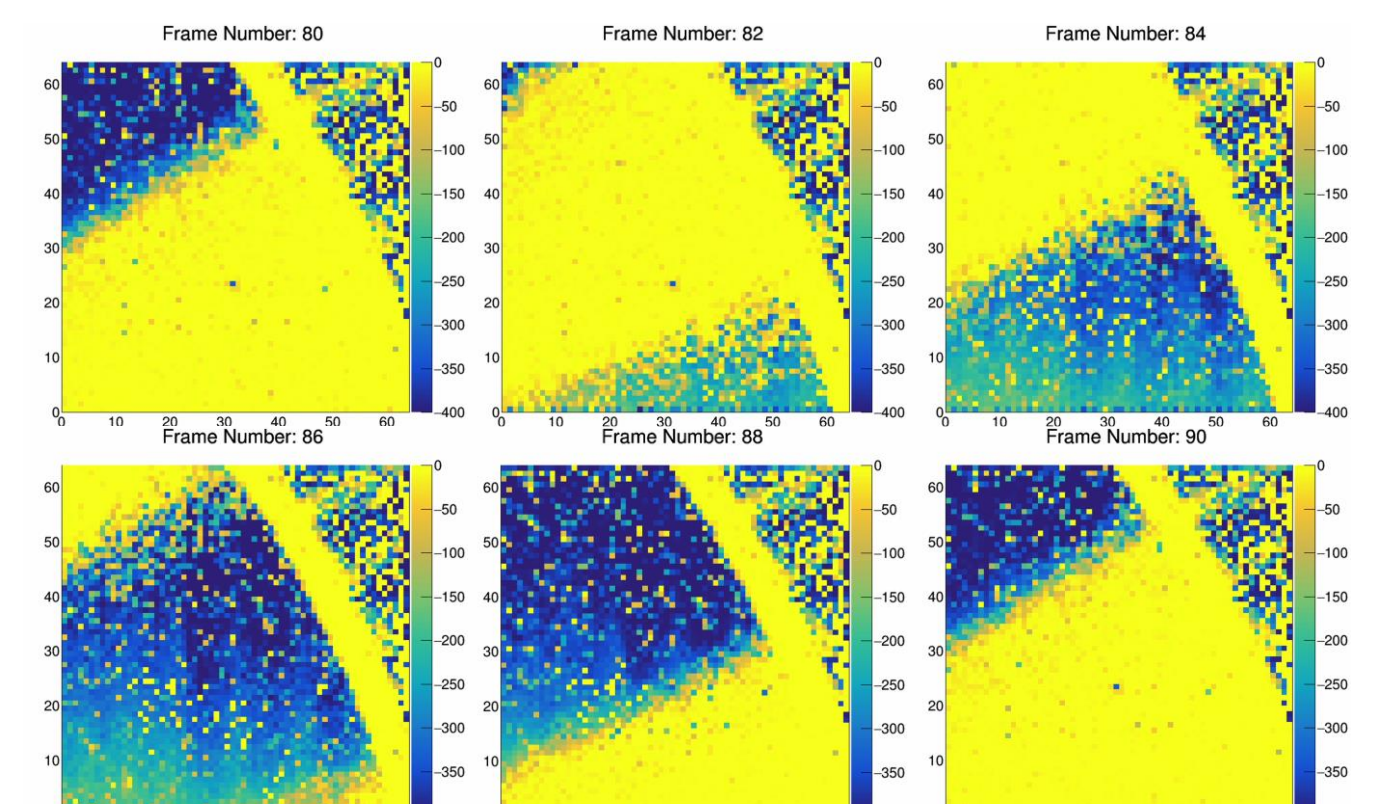


Figure 15 Imaging of a rotating chopper@100Hz, the frame rate is 1kHz

Summary and Outlooks

HYLITE is a charge-integration readout chip designed for STARLIGHT, a pixel array detector for SHINE. In this poster, we present the designs of the first full-scale chip of HYLITE, HYLITE200F, and the corresponding prototype modules. Functionality of the front-end module is verified via preliminary imaging test, while the bump-bonding process still needs to be improved. Meanwhile, the second full-scale chip with a pixel pitch of 100 μm has been manufactured and will be tested soon.